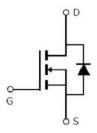


#### Main Product Characteristics:

V <sub>DSS</sub>	650V
R <sub>DS</sub> (on)	0.65Ω (typ.)
ID	<b>10A</b> <sup>①</sup>





TO-220F SSF10N60CFL



#### **Features and Benefits:**

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



### **Description:**

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

### **Absolute Max Rating:**

Symbol	Parameter	Max.	Units	
I <sub>D</sub> @ TC = 25°C	Continuous Drain Current  V <sub>GS</sub> @ 10V	10	^	
Ідм	Pulsed Drain Current 2	38	- A	
P <sub>D</sub> @TC = 25°C	Power Dissipation 3	65	W	
V <sub>DS</sub>	Drain-Source Voltage	650	V	
V <sub>GS</sub>	Gate-to-Source Voltage	± 30	V	
E <sub>AS</sub>	Single Pulse Avalanche Energy @ L=0.5mH	562	mJ	
I <sub>AS</sub>	Avalanche Current	7.5	А	
T <sub>J</sub> T <sub>STG</sub>	T <sub>STG</sub> Operating Junction and Storage Temperature Range		°C	



## **Thermal Resistance**

Symbol	Characterizes	Тур.	Max.	Units
Rejc	Junction-to-case ③	—	1.92	°C <b>/W</b>
R <sub>0JA</sub>	Junction-to-ambient (t $\leq$ 10s) ④	—	62.5	°C/W

### Electrical Characterizes @TA=25°C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source breakdown voltage	650			V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250µA
R <sub>DS(on)</sub>	Static Drain-to-Source on-resistance		0.65	0.8	Ω	V <sub>GS</sub> =10V,I <sub>D</sub> = 3.2A
$V_{GS(th)}$	Gate threshold voltage	2		4	V	$V_{DS} = V_{GS}, I_D = 250 \mu A$
I <sub>DSS</sub>	Drain-to-Source leakage current			1	μA	V <sub>DS</sub> =650V,V <sub>GS</sub> = 0V
		_		100	0	V <sub>GS</sub> = 30V, V <sub>DS</sub> = 0V
I <sub>GSS</sub>	Gate-to-Source forward leakage	_	_	-100	nA	V <sub>GS</sub> = -30V, V <sub>DS</sub> = 0V
Qg	Total gate charge	_	35	_		I <sub>D</sub> = 10A,
Q <sub>gs</sub>	Gate-to-Source charge	_	7	_	nC	V <sub>DS</sub> =520V
Q <sub>gd</sub>	Gate-to-Drain("Miller") charge	_	18	_	]	V <sub>GS</sub> = 10V
t <sub>d(on)</sub>	Turn-on delay time	_	23			
tr	Rise time	_	15	_	]	V <sub>DS</sub> =325V,
t <sub>d(off)</sub>	Turn-Off delay time	_	90	_	ns	R <sub>GEN</sub> =25Ω,I <sub>D</sub> =10A
t <sub>f</sub>	Fall time	_	30	_	]	
Ciss	Input capacitance	_	1264	_		V <sub>GS</sub> = 0V
Coss	Output capacitance	_	149	_	pF	V <sub>DS</sub> = 100V
C <sub>rss</sub>	Reverse transfer capacitance	_	18	_	]	f = 1MHz

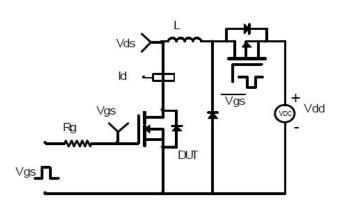
# **Source-Drain Ratings and Characteristics**

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
	Continuous Source Current ①	— — 10		10	٨	MOSFET symbol
Is	(Body Diode)		10 A	A	showing the	
I <sub>SM</sub>	Pulsed Source Current	_	—	38	А	integral reverse
	(Body Diode)					p-n junction diode.
V <sub>SD</sub>	Diode Forward Voltage	—	_	1.4	V	I <sub>S</sub> =7A, V <sub>GS</sub> =0V
t <sub>rr</sub>	Reverse Recovery Time		320		nS	Is=7A,V <sub>GS</sub> =0V,
Qrr	Reverse Recovery Charge	—	4.2		uC	di/dt = 100A/µs



### **Test Circuits and Waveforms**

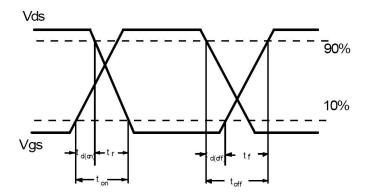
EAS Test Circuit:



Switching Time Test Circuit:

Switching Waveforms:

**Gate Charge Test Circuit:** 



#### Notes:

- ①Calculated continuous current based on maximum allowable junction temperature.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- (④The value of R<sub>θJA</sub> is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25°C



# **Typical Electrical and Thermal Characteristics**

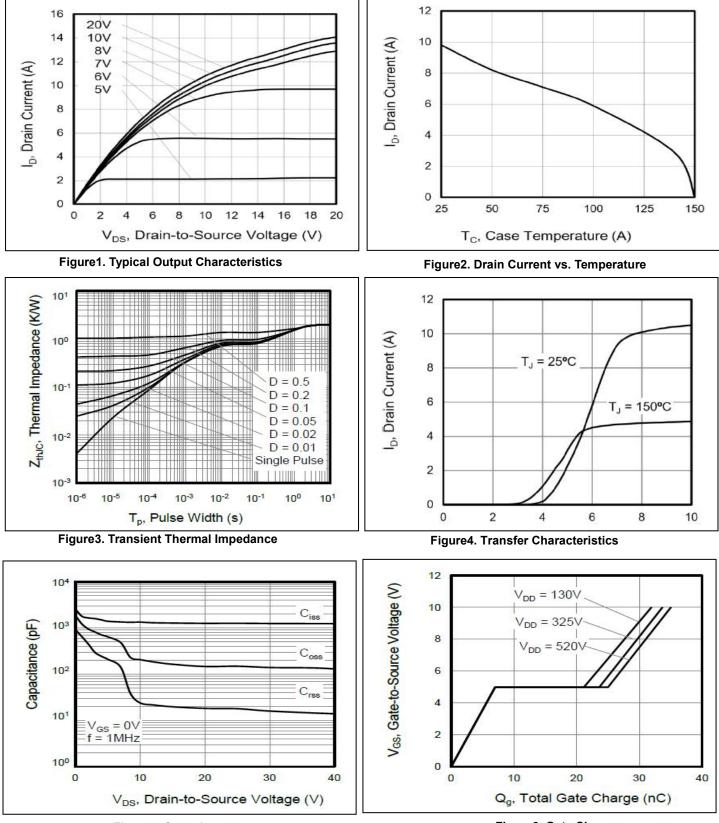


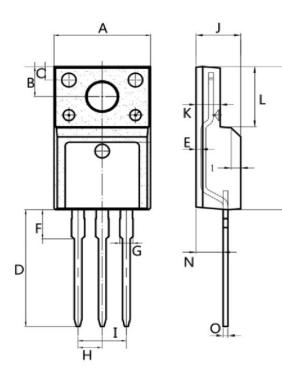
Figure5. Capacitance

Figure6. Gate Charge



### Mechanical Data:

TO-220F Package Outline(Unit:mm)



-				
Dim.	Min.	Max.		
A	9.9	10.3		
В	2.9	3.5		
С	1.15	1.45		
D	12.75	13.25		
E	0.55	0.75		
F	3.1	3.5		
G	1.25	1.45		
Н	Тур 2.54			
I	Typ 5.08			
J	4.55	4.75		
K	2.4	2.7		
L	6.35	6.75		
M	15.0	16.0		
N	2.75	3.15		
0	0.45	0.60		
All Dimensions in millimeter				

м





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